Tata Institute of Fundamental Research
Survey No. 36/P, Gopanpally Village, Serilingampally, Ranga Reddy Dist., Hyderabad - 500107

Seminar

Advanced Applications using Aberration-Corrected Analytical TEM/STEM from JEOL

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JEOL Asia Pte Ltd., Singapore

Examples of application data on advanced materials obtained with aberration-corrected analytical transmission electron microscope (TEM) and scanning transmission electron microscope (STEM) are introduced. One of them is an atomic resolution structure analysis of nano-particles of catalysts. The second one is atomic resolution elemental analysis of ceramics. And also, an In-situ observation of chemical reaction of iron oxide nanoparticles in aberration corrected 300 kV-TEM (JEM-ARM300F) is introduced.

Tuesday, Oct 10th 2017

11:00 AM (Tea/Coffee at 10:45 AM)

Class Room – 4 (G Floor), TIFR-H (FReT-B)